Producer/exporter	Period of review	Weighted-average margin (%)	
		Original:	Revised:
A–588–604			
NTN	10/1/1995—9/30/1996	21.41	21.48
NSK	10/1/1995—9/30/1996	10.17	n/a
A–588–054			
NSK	10/1/1995—9/30/1996	1.64	n/a

Accordingly, the Department has determined and CBP will assess appropriate antidumping duties on the relevant entries of the subject merchandise from NTN and NSK covered by the reviews of the period listed above. The Department will issue assessment instructions directly to CBP within 15 days of publication of this notice.

Dated: June 8, 2004.

James J. Jochum,

Assistant Secretary for Import Administration.

[FR Doc. 04–13988 Filed 6–21–04; 8:45 am]

BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 A.M. and 5 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW., Washington, DC.

Docket Number: 04–010. *Applicant:* Cornell University, 123 Day Hall, Ithaca, NY 14853. *Instrument:* X-ray Double Crystal Monochrometer. *Manufacturer:* Kohzu Precision Co., Ltd., Japan. *Intended Use:* The instrument is intended to be used by a group of universities to study the molecular structure of macro-molecules of importance in the life sciences including proteins, viruses, enzymes and other related entities by the scattering of monoenergetic x-rays from single crystals of these materials utilizing the intense beams of x-rays provided by the Advanced Photon Source at Argonne National Laboratory. *Application accepted by Commissioner of Customs:* May 7, 2004.

Docket Number: 04–011. *Applicant:* Catawba College, 22300 W. Innes Street, Salisbury, NC 28144. *Instrument:* Transmission Electron Microscope, Model Jem-1011. *Manufacturer:* JEOL, Japan. *Intended Use:* The instrument is intended to be used in teaching the techniques and procedures of biological specimen fixation, embedding, sectioning, staining, examination and analysis. It will be used in a course on electron microscopy and in a seminar on biological research. *Application accepted by Commissioner of Customs:* May 19, 2004.

Docket Number: 04–012. *Applicant:* University of California, Los Angeles, Department of Physics and Astronomy, 475 Portola Plaza, Los Angeles, CA 90095–1547. *Instrument:* Dual Beam Electron Microscope/Focused Ion Beam Milling Machine, Model Nova 600 Nanolab. *Manufacturer:* FEI Company, the Netherlands. *Intended Uses:* The instrument is intended to be used:

1. To develop and fine-tune nanometer scale mechanical sensors by standard micro-fabrication processes
2. Machining of probes to study the shape dependence of the cantilever spring constant and to achieve the sharpest tip
3. To achieve subatomic scale resolution with an AFM using the sensors developed. Application accepted by Commissioner of Customs: June 3, 2004.

Docket Number: 04–013. *Applicant:* Cornell University, 123 Day Hall, Ithaca, NY 14853. *Instrument:* X-ray Focusing Mirror System, Model Ne Cat. *Manufacturer:* Oxford-Danfysik, United Kingdom. *Intended Use:* The instrument is intended to be used by a group of universities to study the molecular structure of macro-molecules of importance in the life sciences including proteins, viruses, enzymes and other related entities by the scattering of monoenergetic x-rays from single crystals of these materials utilizing the intense beams of x-rays provided by the Advanced Photon Source at Argonne National Laboratory. The mirror system is needed to focus the intense x-ray beam from the Advanced Photon Source onto millimeter size crystals.

Application accepted by Commissioner of Customs: June 3, 2004.

Gerald A. Zerdy,

Program Manager, Statutory Import Programs Staff.

[FR Doc. 04–13989 Filed 6–21–04; 8:45 am]

BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Export Trade Certificate of Review

ACTION: Notice of application to amend an Export Trade Certificate of Review.

SUMMARY: The Office of Export Trading Company Affairs (''OETCA''), International Trade Administration, U.S. Department of Commerce, has received an application to amend an Export Trade Certificate of Review (''Certificate''). This notice summarizes the proposed amendment and requests comments relevant to whether the Certificate should be issued.

FOR FURTHER INFORMATION CONTACT: Jeffrey Anspacher, Director, Office of Export Trading Company Affairs, International Trade Administration, by phone at (202) 482–5131, (this is not a toll-free number) or by e-mail at *oetca@ita.doc.gov.*

SUPPLEMENTARY INFORMATION: Title III of the Export Trading Company Act of 1982 (15 U.S.C. 4001–21) authorizes the Secretary of Commerce to issue Export Trade Certificates of Review. An Export Trade Certificate of Review protects the holder and the members identified in the Certificate from State and Federal government antitrust actions and from private treble damage antitrust actions for the export conduct specified in the Certificate and carried out in compliance with its terms and conditions. Section 302(b)(1) of the Export Trading Company Act of 1982 and 15 CFR 325.6(a) require the